Fundamentals of Nanoelectronics, Basic Concepts Unit 4 Prof. Supriyo Datta L4.2 Quiz <u>Answers</u>

4.2. Seebeck Coefficient

We have seen that the current can be written in terms of voltage and temperature differences in the form $I = G_0 DV + G_S DT$ Where

$$G_0 = \int_{-\infty}^{+\infty} dE \left(-\frac{\partial f_0}{\partial E} \right) G(E)$$

$$G_{S} = \int_{-\infty}^{+\infty} dE \left(-\frac{\partial f_{0}}{\partial E} \right) \frac{E - M_{0}}{qT_{0}} G(E)$$

4.2a A device with the source hotter than the drain is left open-circuited so that current is *zero*. Relative to the source, the drain will become

(a) Negative, always

(b) Positive, always

(c) Positive, if G(E) increases with increasing E around $E=\mu$

(d) Negative, if G(E) increases with increasing E around $E=\mu$

(e) none of the above, drain and source have the same potential.

4.2b The magnitude of the Seebeck coefficient S is given by

- (a) $|S| = \frac{G_S}{G_0}$ (b) $|S| = G + G_S$ (c) $|S| = G - G_S$ (d) $|S| = G * G_S$
- (e) S is unrelated to G and Gs